



ASSOCIATION CONNECTING  
ELECTRONICS INDUSTRIES®

**IPC-2226**

# **Sectional Design Standard for High Density Interconnect (HDI) Printed Boards**

Developed by the HDI Design Subcommittee (D-41) of the HDI  
Committee (D-40) of IPC

Users of this standard are encouraged to participate in the  
development of future revisions.

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# Table of Contents

<b>1</b>	<b>SCOPE</b>	1	4.5	Embedded Electronic Components	12
1.1	Purpose	1	4.5.1	Embedded Resistors	12
1.2	Document Hierarchy	1	4.5.2	Embedded Capacitors	12
1.3	Presentation	1	4.5.3	Embedded Inductors	13
1.4	Interpretation	1	<b>5</b>	<b>MECHANICAL/PHYSICAL PROPERTIES</b>	13
1.5	Classification of HDI Types	1	5.1	HDI Feature Size	13
1.5.1	Core Types	1	5.1.1	Minimum Hole Sizes for Plated-Through Hole Vias	13
1.5.2	HDI Types	1	5.2	Construction Types	13
1.6	Via Formation	1	5.2.1	HDI Type I Constructions - 1 [C] 0 or 1 [C] 1	13
1.7	Design Features	1	5.2.2	HDI Type II Constructions - 1 [C] 0 or 1 [C] 1	13
<b>2</b>	<b>APPLICABLE DOCUMENTS</b>	1	5.2.3	HDI Type III Constructions - $\geq 2$ [C] $\geq 0$	13
2.1	IPC	1	5.2.4	HDI Type IV Constructions - $\geq 1$ [P] $\geq 0$	15
2.2	Underwriters Laboratories	2	5.2.5	Type V Constructions (Coreless) - Using Layer Pairs	15
<b>3</b>	<b>GENERAL REQUIREMENTS</b>	2	5.2.6	Type VI Constructions	17
3.1	Terms and Definitions	2	<b>6</b>	<b>ELECTRICAL PROPERTIES</b>	19
3.1.1	Microvia (Build-Up Via)	2	6.1	Equivalent Circuitry	19
3.1.2	Capture Land (Via Top Land)	2	6.2	Final Metal Traces	19
3.1.3	Target Land (Via Bottom Land)	2	6.2.1	Inductance and Capacitance	19
3.1.4	Stacked Vias	3	6.2.2	High Frequency Performance	21
3.1.5	Stacked Microvias	3	<b>7</b>	<b>THERMAL MANAGEMENT</b>	21
3.1.6	Staggered Vias	3	7.1	Thermal Management Concerns for Bump Interconnects on HDI	22
3.1.7	Staggered Microvias	3	7.1.1	Junction to Case Thermal Models	23
3.1.8	Variable Depth Microvia/Via	3	7.2	Thermal Flow Management Through HDI Substrate	24
3.2	Design Tradeoffs	3	<b>8</b>	<b>COMPONENT AND ASSEMBLY ISSUES</b>	27
3.3	Design Layout	5	8.1	General Attachment Requirements	27
3.3.1	Design Considerations	5	8.1.1	Flip Chip Design Considerations	27
3.4	Density Evaluation	5	8.1.2	Chip Size Standardization	27
3.4.1	Routability Prediction Methods	5	8.1.3	Bump Site Standards	28
3.4.2	Design Basics	6	8.1.4	Bump Options	29
<b>4</b>	<b>MATERIALS</b>	8	8.2	Chip Scale Design Considerations	31
4.1	Material Selection	8	8.2.1	Chip Scale Area Arrays (FBGA and FLGA)	32
4.1.1	HDI Material Options	8	8.2.2	Peripheral Ledged Chip Scale Packages (TSOJ and SOC)	32
4.1.2	Designation System	9	8.3	Printed Board Land Pattern Design	32
4.2	Application Levels	11	8.4	Substrate Structure Standard Grid Evolution	32
4.3	Material Description by Type	11	8.4.1	Footprint Design	33
4.3.1	Dielectric Materials	11	8.4.2	Design Guide Checklist	33
4.3.2	Materials for Conductive Paths (In-Plane or Inter-Plane)	11			
4.3.3	Materials with Dielectric and Conductive Functionality	12			
4.4	Copper Foil	12			
4.4.1	Pits, Dents and Pinholes	12			

8.4.3 Footprint Population ..... 33

**9 HOLES/INTERCONNECTIONS ..... 35**

9.1 Microvias ..... 35

9.1.1 Microvia Formation ..... 36

9.2 Via Interconnect Variations ..... 37

9.2.1 Stacked Microvias ..... 37

9.2.2 Stacked Vias ..... 38

9.2.3 Staggered Microvias ..... 38

9.2.4 Staggered Vias ..... 38

9.2.5 Variable Depth Vias/Microvias ..... 39

**10 GENERAL CIRCUIT FEATURE REQUIREMENTS ..... 41**

10.1 Conductor Characteristics ..... 41

10.1.1 Balanced Conductors ..... 41

10.2 Land Characteristics ..... 41

10.3 Determining the Number of Conductors ..... 41

10.4 Wiring Factor (Wf) ..... 41

10.4.1 Localized Escape Calculations ..... 41

10.4.2 Wiring Between Tightly Linked Components .. 43

10.4.3 Total Wiring Requirements ..... 43

10.5 Via and Land Density ..... 44

10.6 Trade Off Process ..... 44

10.6.1 Wiring Factor Process ..... 44

10.6.2 Input/Output (I/O) Variables ..... 44

**11 DOCUMENTATION ..... 45**

**12 QUALITY ASSURANCE ..... 45**

Figure 5-4 Type III HDI Construction with Stacked Microvias (Caution: Unbalanced constructions may result in warp & twist.) ..... 17

Figure 5-5 Type III HDI Construction with Staggered Microvias (Caution: Unbalanced constructions may result in warp & twist.) ..... 17

Figure 5-6 Type III HDI with Variable Depth Blind Vias .... 17

Figure 5-7 Type IV HDI Construction ..... 18

Figure 5-8 Coreless Type V HDI Construction ..... 18

Figure 5-9 Type VI Construction ..... 18

Figure 6-1 Bump Electrical Path (Redistributed Chip) ..... 20

Figure 6-2 Final Metal Trace and Underlying Traces (Cross Section) ..... 20

Figure 7-1 HDI Thermal Path Relationships ..... 22

Figure 7-2 Thermal Management of Chip Scale and Flip Chip Parts Mounted on HDI ..... 22

Figure 7-3 Bump Interconnect Equivalent Model ..... 23

Figure 7-4 Wire Bond Example ..... 24

Figure 7-5 Approximate Thermal Model for Wire Bond .... 24

Figure 7-6 Flip Chip Example ..... 25

Figure 7-7 Approximate Thermal Model for Flip Chip ..... 25

Figure 7-8 Chip Underfill Example ..... 25

Figure 7-9 Approximate Thermal Model for Chip Underfill ..... 25

Figure 7-10 Thermal Paste Example ..... 25

Figure 7-11 Approximate Thermal Model for Thermal Paste ..... 26

Figure 7-12 Thermal Resistance ..... 26

Figure 7-14 Metallic Thermal Properties ..... 26

Figure 7-13 Parallel Resistances ..... 26

Figure 8-1 Flip Chip Connection ..... 27

Figure 8-2 Mechanical and Electrical Connections ..... 27

Figure 8-3 Joined Chip and Chip Underfill ..... 27

Figure 8-4 Example Layouts ..... 28

Figure 8-5 Suggested Direct Chip Attach Grid Pitch (250 μm [9,843 μin] Grid; 150 μm [5,906 μin] Bumps) ..... 30

Figure 8-6 Type of CSP ..... 31

Figure 8-7 Chip Scale Peripheral Package ..... 32

Figure 8-8 Printed Board Flip Chip or Grid Array Land Patterns ..... 32

Figure 8-9 MSMT Land Drawing and Dimensions ..... 33

Figure 8-10 Standard Grid Structure ..... 34

Figure 8-11 Bump Footprint Planning ..... 34

Figure 8-12 Redundant Footprint ..... 34

Figure 8-13 Design Shrink Footprint ..... 35

Figure 8-14 Signal and Power Distribution Position ..... 35

Figure 8-15 Nested I/O Footprint ..... 35

Figure 9-1 Summary of the Manufacturing Processes for PIDs, Laser and Plasma Methods of Via Generation ..... 36

Figure 9-2 Microvia Manufacturing Processes ..... 37

**Figures**

Figure 1-1 Color Key ..... 2

Figure 3-1 Staggered Via ..... 3

Figure 3-2 Staggered Microvias ..... 3

Figure 3-3 Package Size and I/O Count ..... 6

Figure 3-4 Feature Pitch and Feature Size Defining Channel Width ..... 6

Figure 3-5 Routing and Via Grid for BGA Package ..... 7

Figure 3-6 Feature Pitch and Conductor Per Channel Combinations ..... 8

Figure 4-1 PCB-HDI/Microvia Substrate (Application H) ... 11

Figure 4-2 IC Carrier on HDI/Microvia Substrate (Application I) ..... 11

Figure 4-3 BGA Package on MCM-L Substrate Using HDI-PCB Technology (Application I) ..... 11

Figure 5-1 Type I HDI Construction ..... 15

Figure 5-2 Type II HDI Construction ..... 16

Figure 5-3 Type III HDI Construction (Caution: Unbalanced constructions may result in warp & twist.) ..... 16

Figure 9-3	Cross-Sectional Views of Methods to Make HDI with Microvias .....	37	Table 5-2	Minimum Drilled Hole Size for Plated-Through Hole Vias .....	15
Figure 9-4	Four Typical Constructions that Employ Lasers for Via Generation .....	38	Table 6-1	Final Metal Signal Trace (30 $\mu\text{m}$ [1,181 $\mu\text{in}$ ]) Resistances (example) .....	21
Figure 9-5	Four Typical Constructions Utilizing Etched or Mechanically Formed Vias .....	38	Table 6-2	Final Metal Power Trace (60 $\mu\text{m}$ [0.00236 in]) Resistances (example) .....	21
Figure 9-6	Four Commercially Produced PID Boards .....	39	Table 7-1	Typical Thermal Resistance for Variable Bump Options (Triple Layer Chip) .....	23
Figure 9-7	Four New HDI Boards that Employ Conductive Pastes as Vias .....	39	Table 7-2	Typical Bump (150 $\mu\text{m}$ ) [5,906 $\mu\text{in}$ ] Thermal Resistance Multilayer Metal Chips .....	23
Figure 9-8	Stacked Microvias .....	39	Table 8-1	Pitch Dimensions .....	28
Figure 9-9	Stacked Vias .....	40	Table 8-2	Examples of Fixed Square Body Size Showing Maximum I/O Capability .....	29
Figure 9-10	Staggered Microvias .....	40	Table 8-3	Example of Fixed Rectangular Body Size .....	30
Figure 9-11	Isometric View of Staggered Vias .....	40	Table 8-4	Bump Diameter and Minimum Pitch Options ...	30
Figure 9-12	Variable Depth Vias/Microvias .....	41	Table 8-5	Chip Edge Seal Dimensions (Typical) .....	33
Figure 10-1	Wiring Factor Model for Tightly Coupled Components .....	44	Table 10-1	Number of Conductors for Gridded Router When Feature Pitch is 2,500 $\mu\text{m}$ [98,425 $\mu\text{in}$ ] ..	42
Figure 10-2	Wiring Process Flow Chart .....	45	Table 10-2	Number of Conductors for Gridded Router When Feature Pitch is 1,250 $\mu\text{m}$ [49,213 $\mu\text{in}$ ] ..	42

### Tables

Table 3-1	PCB Design/Performance Tradeoff Checklist .....	3	Table 10-3	Number of Conductors for Gridded Router When Feature Pitch is 650 $\mu\text{m}$ [25,591 $\mu\text{in}$ ] .....	42
Table 4-1	Sample Dielectric Insulator Designation .....	9	Table 10-4	Number of Conductors for Gridded Router When Feature Pitch is 500 $\mu\text{m}$ [19,685 $\mu\text{in}$ ] .....	42
Table 4-2	Sample Conductor Designation .....	9	Table 10-5	Number of Conductors for Gridded Router When Feature Pitch is 250 $\mu\text{m}$ [9,843 $\mu\text{in}$ ] .....	43
Table 4-3	Dielectric with Conductor Designations .....	9	Table 10-6	Pad Rows that can Escape per HDI Layer for Different Feature Sizes .....	43
Table 5-1	Typical Feature Sizes for HDI Construction, $\mu\text{m}$ [mil] .....	14	Table 10-7	Efficiencies .....	44

# Sectional Design Standard for High Density Interconnect (HDI) Printed Boards

## 1 SCOPE

This standard establishes requirements and considerations for the design of organic and inorganic high density interconnect (HDI) printed boards and its forms of component mounting and interconnecting structures.

**1.1 Purpose** The requirements contained herein are intended to establish design principles and recommendations that **shall** be used in conjunction with the detailed requirements of IPC-2221. In addition, when the core material reflects requirements identified in the sectional standards (IPC-2222, IPC-2223, IPC-2224 and IPC-2225), that information becomes a mandatory part of this standard.

The standard provides recommendations for signal, power, ground and mixed distribution layers, dielectric separation, via formation and metallization requirements and other design features that are necessary for HDI-advanced IC interconnection substrates. Included are trade-off analyses required to match the mounting structure to the selected chip set.

**1.2 Document Hierarchy** Document hierarchy **shall** be in accordance with the generic standard IPC-2221.

**1.3 Presentation** All dimensions and tolerances in this standard are represented in SI (metric) units with Imperial units following as a hard conversion for reference only (e.g., 0.01 cm [0.0039 in]).

**1.4 Interpretation** Interpretation **shall** be in accordance with the generic standard IPC-2221.

**1.5 Classification of HDI Types** Classification **shall** be by category in accordance with the requirements based on end use and as stated in 1.5.1 and 1.5.2 of this standard.

**1.5.1 Core Types** When HDI products utilize core interconnections, the core type(s) and their materials **shall** be in accordance with IPC-2222 for rigid and IPC-2223 for flexible core interconnections. For passive or constraining core boards the materials **shall** be in accordance with IPC-2221.

**1.5.2 HDI Types** The design designation system of this standard recognizes the six industry approved design types (see 5.2) used in the manufacture of HDI printed boards.

The designations in this section determine the HDI design type by defining the number and location of HDI layers that may or may not be combined with a substrate (core [C] or passive [P]).

For instance, an HDI printed board with two layers of HDI on one side of the core and one layer of HDI on the other side of the core would be 2 [C] 1.

The following definitions apply to all forms of HDI.

**TYPE I** 1 [C] 0 or 1 [C] 1 - with through vias connecting the outer layers (see 5.2.1).

**TYPE II** 1 [C] 0 or 1 [C] 1 - with buried vias in the core and may have through vias connecting the outer layers (see 5.2.2).

**TYPE III**  $\geq 2$  [C]  $\geq 0$  - may have buried vias in the core and may have through vias connecting the outer layers (see 5.2.3).

**TYPE IV**  $\geq 1$  [P]  $\geq 0$  - where P is a passive substrate with no electrical connection (see 5.2.4).

**TYPE V** Coreless constructions using layer pairs (see 5.2.5).

**TYPE VI** Alternate constructions (see 5.2.6).

**1.6 Via Formation** Via formation may be different from that considered in IPC-2221 since additional methods for via formation, in addition to drilled vias, will be used. The methods for via formation, lamination/coating and sequential layer process are covered in 9.1.1.

**1.7 Design Features** Figure 1-1 provides a color key to be used with all of the figures within this standard.

## 2 APPLICABLE DOCUMENTS

The following documents form a mandatory part of this standard and all requirements stated therein apply, unless modified in the section where they are invoked.

The revision of the document in effect at the time of solicitation **shall** take precedence over the applicable section of this document.

### 2.1 IPC<sup>1</sup>

**IPC-T-50** Terms and Definitions for Interconnecting and Packaging Electronic Circuits

1. www.ipc.org